United States Design Patent
Chang et al.

Microscope Measurement Apparatus

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Field of Classification Search
CPC ........ G01B 5/008; G01B 5/016; G01B 11/03; G01B 11/24; G05B 19/401; G05B 19/4207; G02B 21/082; G02B 21/241; G02B 21/0016; G02B 21/0076; G02B 21/086; G02B 21/16
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See application file for complete search history.

References Cited

U.S. PATENT DOCUMENTS

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Claim
The ornamental design for a microscope measurement apparatus, as shown and described.

Description

Fig. 1 is a perspective view of a microscope measurement apparatus showing our new design;
Fig. 2 is a front elevational view thereof;
Fig. 3 is a rear elevational view thereof;
Fig. 4 is a left side elevational view thereof;
Fig. 5 is a right side elevational view thereof;
Fig. 6 is a top plan view thereof; and,
Fig. 7 is a bottom plan view thereof.

1 Claim, 7 Drawing Sheets